

October 2006
FRFET**

FQB9N50CF 500V N-Channel MOSFET

Features

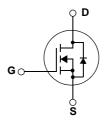
- 9A, 500V, $R_{DS(on)} = 0.85 \Omega @V_{GS} = 10 V$
- Low gate charge (typical 28nC)
- Low Crss (typical 24pF)
- · Fast switching
- 100% avalanche tested
- · Improved dv/dt capability

Description

These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency switched mode power supplies, electronic lamp ballasts based on half bridge topology.





Absolute Maximum Ratings

Symbol	Parameter	FQB9N50CF	Units	
V _{DSS}	Drain-Source Voltage	500	V	
I _D	Drain Current - Continuous (T _C = 25°C)		9	Α
	- Continuous (T _C = 100°C)		5.7	Α
I _{DM}	Drain Current - Pulsed	(Note 1)	36	А
V _{GSS}	Gate-Source Voltage		± 30	V
E _{AS}	Single Pulsed Avalanche Energy	(Note 2)	300	mJ
I _{AR}	Avalanche Current	(Note 1)	5	А
E _{AR}	Repetitive Avalanche Energy	(Note 1)	9.6	mJ
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	4.5	V/ns
P_{D}	Power Dissipation (T _C = 25°C)		173	W
	- Derate above 25°C		1.38	W/°C
T _J , T _{STG}	Operating and Storage Temperature Range		-55 to +150	°C
TL	Maximum lead temperature for soldering purpose 1/8" from case for 5 seconds	s,	300	°C

Thermal Characteristics

Symbol	Parameter	FQB9N50CF	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	0.72	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient*	40	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	62.5	°C/W

 $^{^{\}star}$ When mounted on the minimum pad size recommended (PCB Mount)

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FQB9N50CF	FQB9N50CFTM	D2-PAK	330mm	24mm	800
FQB9N50CFS	FQB9N50CFTM_WS	D2-PAK	330mm	24mm	800

Electrical Characteristics $T_C = 25$ °C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Charac	teristics				1	-
BV _{DSS}	Drain-Source Breakdown Voltage	V_{GS} = 0 V, I_{D} = 250 μ A	500			V
$\Delta BV_{DSS}/$ ΔT_J	Breakdown Voltage Temperature Coefficient	I _D = 250 μA, Referenced to 25°C		0.57		V/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 500 V, V _{GS} = 0 V			10	μΑ
		V _{DS} = 400 V, T _C = 125°C			100	μΑ
I _{GSSF}	Gate-Body Leakage Current, Forward	V _{GS} = 30 V, V _{DS} = 0 V			100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	V _{GS} = -30 V, V _{DS} = 0 V			-100	nA
On Charact	eristics					
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	2.0		4.0	V
R _{DS(on)}	Static Drain-Source On-Resistance	V _{GS} = 10 V, I _D = 4.5A		0.7	0.85	Ω
9 _{FS}	Forward Transconductance	V _{DS} = 40 V, I _D = 4.5 A (Note 4)		6.5		S
Dynamic Cl	haracteristics					
C _{iss}	Input Capacitance	V _{DS} = 25 V, V _{GS} = 0 V,		790	1030	pF
C _{oss}	Output Capacitance	f = 1.0 MHz		130	170	pF
C _{rss}	Reverse Transfer Capacitance			24	30	pF
Switching C	Characteristics					
t _{d(on)}	Turn-On Delay Time	V _{DD} = 250 V, I _D = 9A,		18	45	ns
t _r	Turn-On Rise Time	$R_G = 25 \Omega$		65	140	ns
t _{d(off)}	Turn-Off Delay Time			93	195	ns
t _f	Turn-Off Fall Time	(Note 4, 5)		64	125	ns
Q_g	Total Gate Charge	V _{DS} = 400 V, I _D = 9A,		28	35	nC
Q_{gs}	Gate-Source Charge	V _{GS} = 10 V		4		nC
Q_{gd}	Gate-Drain Charge	(Note 4, 5)		15		nC
Drain-Source	ce Diode Characteristics and Maximum Ratings					
I _S	Maximum Continuous Drain-Source Diode Fo	rward Current			9	Α
I _{SM}	Maximum Pulsed Drain-Source Diode Forwar	d Current			36	Α
V_{SD}	Drain-Source Diode Forward Voltage	V _{GS} = 0 V, I _S = 9 A			1.4	V
t _{rr}	Reverse Recovery Time	V _{GS} = 0 V, I _S = 9 A,		100		ns
Q _{rr}	Reverse Recovery Charge	$dI_F / dt = 100 A/\mu s$ (Note 4)		300		nC

- 1. Repetitive Rating : Pulse width limited by maximum junction temperature
- 2. L = 8mH, I $_{AS}$ = 9A, V $_{DD}$ = 50V, R $_{G}$ = 25 Ω , Starting T $_{J}$ = 25°C
- 3. $I_{SD} \le 9A$, di/dt $\le 200A/\mu s$, $V_{DD} \le BV_{DSS}$, Starting T_J = 25°C
- 4. Pulse Test : Pulse width $\leq 300 \mu s$, Duty cycle $\leq 2\%$
- 5. Essentially independent of operating temperature

Typical Performance Characteristics

Figure 1. On-Region Characteristics

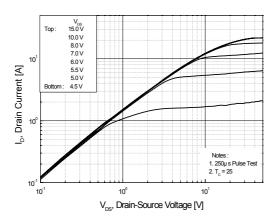


Figure 3. On-Resistance Variation vs.
Drain Current and Gate Voltage

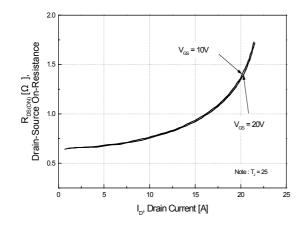


Figure 5. Capacitance Characteristics

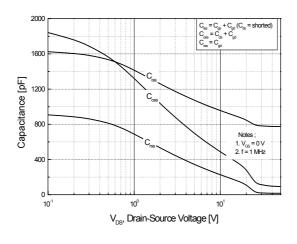


Figure 2. Transfer Characteristics

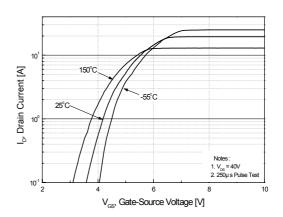


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperatue

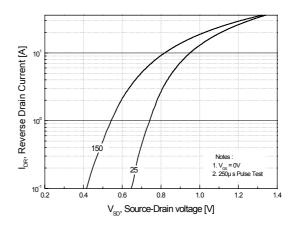
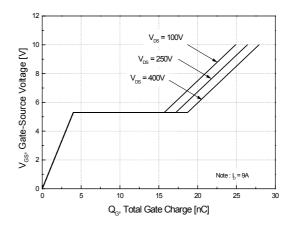


Figure 6. Gate Charge Characteristics



Typical Performance Characteristics (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

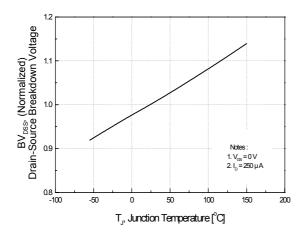


Figure 9. Maximum Safe Operating Area

Figure 8. On-Resistance Variation vs. Temperature

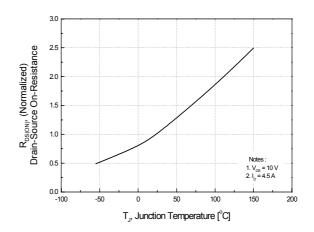


Figure 10. Maximum Drain Current vs. Case Temperature

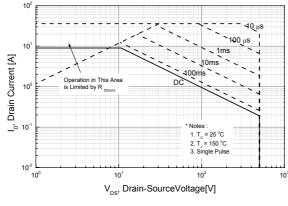
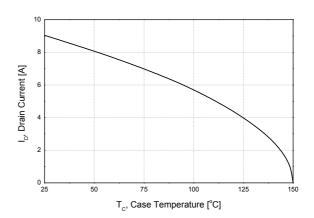
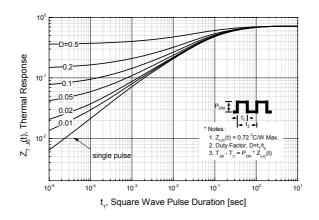
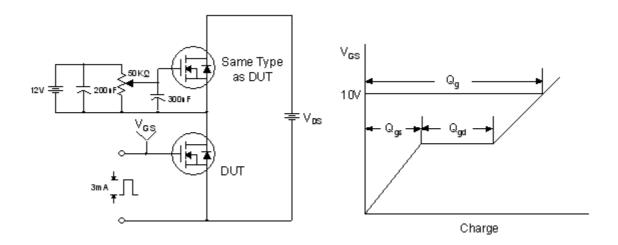


Figure 11. Transient Thermal Response Curve

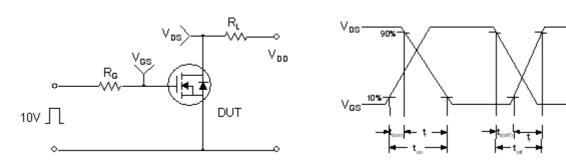




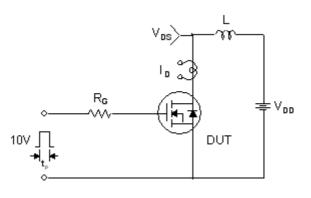
Gate Charge Test Circuit & Waveform

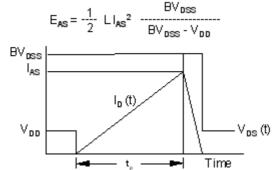


Resistive Switching Test Circuit & Waveforms

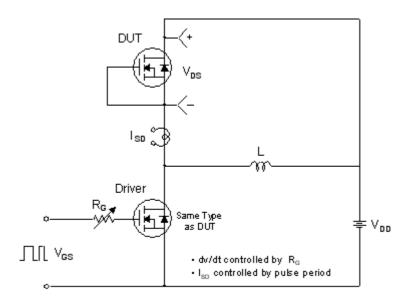


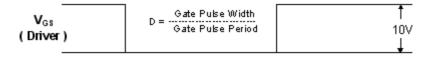
Unclamped Inductive Switching Test Circuit & Waveforms

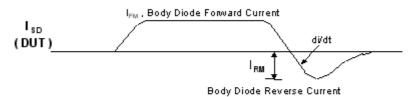


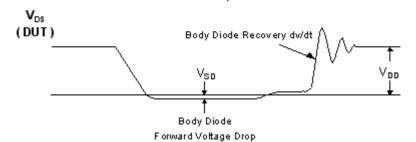


Peak Diode Recovery dv/dt Test Circuit & Waveforms



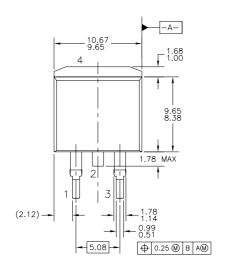


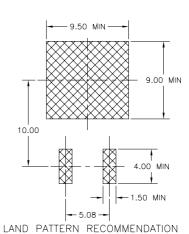


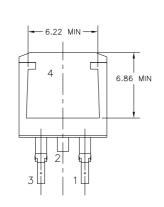


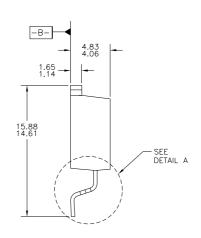
Mechanical Dimensions

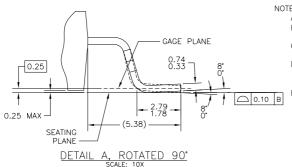
D2-PAK











TO263A02REVD

- NOTES: UNLESS OTHERWISE SPECIFIED

 A) ALL DIMENSIONS ARE IN MILLIMETERS.

 B) REFERENCE JEDEC, TO-263, ISSUE D, VARIATION AB, DATED JULY 2003.

 C) DIMENSIONING AND TOLERANCING PER ANSI Y14.5M 1982.

 D) LOCATION OF THE PIN HOLE MAY VARY (LOWER LEFT CORNER, LOWER CENTER AND CENTER OF THE PACKAGE).

 B E) PRESENCE OF TRIMMED CENTER LEAD IS OPTIONAL.

Dimensions in Millimeters

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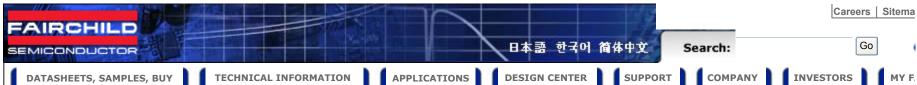
PRODUCT STATUS DEFINITIONS

Definition of Terms

Datasheet Identification	Product Status	Definition
Advance Information	Formative or In Design	This datasheet contains the design specifications for product development. Specifications may change in any manner without notice.
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FQB9N50CF

500V N-Channel MOSFET

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General description

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Product status/pricing/packaging

BUY

Product	Product status	Pb-free Status	Pricing*	Package type	Leads	Packing method	Package Marking Convention**

FQB9N50CFTM	Full Production	Full Production	\$1.40	TO-263(D2PAK)	2	TAPE REEL	Line 1: \$Y (Fairchild logo) & Z (Asm. Plant Code) &E& 3 (3-Digit Date Code) Line 2: FQB Line 3: 9N50CF
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^{*} Fairchild 1,000 piece Budgetary Pricing

** A sample button will appear if the part is available through Fairchild's on-line samples program. If there is no sample button, please contact a Fairchild distributor to obtain samples



Indicates product with Pb-free second-level interconnect. For more information click here.

Package marking information for product FQB9N50CF is available. Click here for more information .

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Qualification Support

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FQB9N50CFTM

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